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EMC SHIELDING EFFECTIVENESS TEST REPORT

Test Specification : MIL-DTL-83528E

Manufacturer : Specialty Silicone Products, Inc

Test Samples :

1. SSP550-45

DOCUMENT HISTORY				
REVISION	REVISION ISSUE DATE AFFECTED PAGE(S)		DESCRIPTION OF MODIFICATIONS	REVISED BY
1.0	12 March 2004		Initial release	



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TEST REPORT NO. 21327-1 from D.L.S. Electronic Systems, Inc.

Test for Specialty Silicone Products, Inc.

REVIEWED BY	REVIEWED BY
Jack Prawica	Brian Mattson

TEST PERSONNEL	TITLE	
Jereme Irwin	EMC Test Engineer	

TEST DATE(S)	October 2, 2015
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TEST FACILITY ADDRESS CITY, STATE, ZIP CODE PHONE

FAX

D.L.S. Electronic Systems, 1250 Peterson Drive Wheeling, IL. 60090 (847) 537-6400 (847) 537-6488

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EMC Shielding Effectiveness Test Report
Gasket Materials
TO MIL-DTL 83528E

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ADMINISTRATIVE SUMMARY

REASON FOR TEST:

To test the shielding effectiveness of one material as specified in MIL-DTL-83528E.

TEST SPECIFICATION:

MIL-DTL 83528E GASKETING MATERIAL, CONDUCTIVE, SHIELDING GASKET, ELECTRONIC, ELASTOMER, EMI/RFI GENERAL SPECIFICATION

DATE(S) OF TEST:

October 2, 2015

TEST SAMPLES:

A total of one sample was presented for testing. Refer to Section 2 of this report for a description of each test sample along with the manufacturer's designation.

MANUFACTURER: Specialty Silicone Products, Inc

Corporate Technology Park

3 McCrea Hill Road Ballston Spa, NY 12020

MANUFACTURERS REPRESENTATIVE:

Dominic J Testo

DISPOSITION OF TEST SAMPLE:

Samples will be returned to SSP, Inc.

TEST LOCATION:

D.L.S. Electronic Systems, 1250 Peterson Drive Wheeling, IL. 60090

TEST PERSONNEL:

Jereme Irwin EMC Test Engineer

SUMMARY OF TEST RESULTS:

The shielding effectiveness of the test sample can be found in data sheets located in Appendix C of this report.



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INTRODUCTION

This report documents the results of a series of EMI/EMC measurements performed on the test samples described in Section 2 of this report. The purpose of this series of tests was to demonstrate compliance of the test sample(s) with the requirements of MIL-DTL-83528E Specification for comparison data of one test sample using a MIL-DTL-83528E test fixture.

SECTIONS

SECTION 1 - CLIENT INFORMATION

COMPANY NAME ADDRESS CITY, STATE ZIP	Specialty Silicone Products, Inc Corporate Technology Park 3 McCrea Hill Road Ballston Spa, NY 12020
CONTACT NAME TITLE PHONE E-MAIL	Dominic J Testo Account Representative (518) 363-5034 DTesto@sspinc.com

CITY, STATE ZIP Ballston Spa, NY 12020	MANUFACTURER ADDRESS CITY, STATE ZIP	3 McCrea Hill Road
Bailstoff Spa, 111 12020		Ballstoff 5pa, 111 12020

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SECTION 2 - PURPOSE OF TEST

The purpose of this series of tests was to verify the shielding effectiveness of the one sample for comparison to MIL-DTL-83528E.

SECTION 3 - TEST SAMPLE DESCRIPTION

The following table provides a list of each type of Gasket Material tested.

NO.	Material	Description
1.	SSP550-45 silver aluminum filled fluorosilicone	26" x 26" Gasket

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SECTION 4 - TEST SITE; FACILITIES, CONDITIONS AND TOLERANCES

The EMI measurements were performed through a test fixture designed to the MIL-DTL-83528E test specification. A modified MIL-DTL-83528E test fixture was located between two adjacent shielded enclosures. The receive chamber and the control (transmit) chamber meets the applicable requirements of NSA65-6. AC power is supplied to each enclosure from a dedicated isolation transformer through low-pass line filters, which provide a minimum of 120 dB of attenuation from 10 kHz to 10 GHz.

SECTION 5 - TEST EQUIPMENT

A complete test system equipment list is provided in APPENDIX A of this report. The equipment absolute performance calibration, of the equipment requiring calibration, is performed on an as needed basis in accordance with MIL-STD-45662. However, calibration periods do not exceed one (1) year. The test equipment is capable of making measurements within tolerances of at least +/- 2 dB amplitude and +/-2% frequency deviation. Equipment certifications showing traceability to NIST (National Institute of Standards and Technology) are maintained on file at D.L.S. Electronic Systems in Wheeling, IL. All equipment is checked and verified for proper operation before and after each series of tests.



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SECTION 6 - TEST RESULTS

The following table lists the requirements and results for each of the test samples.

NO.	Material	BEST ATTENUATION LEVEL (dB)
1.	SSP550-45 silver aluminum filled fluorosilicone	137.8@80MHz

The Specialty Silicone Products, Inc. SSP550-45 was tested to 20MHz-10GHz. The results were greater than 120dB of shielding effectiveness for all frequencies tested.

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SECTION 7 - SHIELDING EFFECTIVENESS MEASUREMENTS

Detailed data sheets, which provide the entire shielding effectiveness results across the entire frequency range for each of the two samples, are provided in APPENDIX C of this report. The following information provides a description of the test data sheet information.

All amplitude measurement levels are recorded in dBuV. Attenuation Levels are recorded in dB.

The data sheets contain the following categories:

- Frequency: Discreet frequency at which measurement was made. Recorded as MHz or GHz.
- Reference Level: Test level with shielding material not in place. This is an amplitude level recorded in dBuV.
- Attenuation: Added attenuation (20dB) to input of receiver when measuring the reference level so not to damage receiver; attenuation removed for testing of gasket. This value is added to the test level.
- For the test Level: Measurement made with shielding material in the test fixture. This is an amplitude level recorded in dBuV.
- > Shielding Effectiveness: Equal to [Reference Level minus the (Test Level minus the pre-amp)]. The result is in dB units.

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APPENDIX A - TEST EQUIPMENT

A.1 Specific Equipment Used

Description	Manufacturer	Cal Due	Frequency	Model L	Jse	Serial No.
Amplifier, RF, Power	Amplifier Research	N/A	10kHz-220MHz	2500LM11	TX	22714
Amplifier, RF, Power	Amplifier Research	N/A	100-1000MHz	1000W1000M7	TX	22243
Antenna, Horn	ETS Lindgren	N/A	20-300MHz	3109	TX	9803-3163
Antenna, Horn	ETS Lindgren	11/14/2015	20-300MHz	BIA-25	RX	2727
Antenna, Horn	ETS Lindgren	N/A	200-2000MHz	3106	TX	42811
Antenna, Horn	ETS Lindgren	11/10/2015	200-2000MHz	3106	RX	2127
Antenna, Horn	ETS Lindgren	N/A	1-18Ghz	3117	TX	135193
Antenna, Horn	ETS Lindgren	8/14/2016	1-18GHz	3117	RX	55158
Pre-Amp	Planar	3/26/2016	1-20GHz	PTB-35-120-5R	0-1 RX	PL3159
Generator, Signal	Rohde & Schwarz	03/23/2016	9kHz-1GHz	SML 03	TX	100025
Generator, Microwave	Rohde & Schwarz	06/25/2016	1-40GHz	SMR 40	TX	100321
Spectrum Analyzer, RF	Agilent	08/25/2016	3Hz-44GHz	E4440A	RX	MY46180453

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APPENDIX B - DESCRIPTION OF TEST METHODS

B.1 SHIELDING EFFECTIVENESS MEASUREMENTS

The shielding effectiveness measurements were made in accordance with MIL-DTL-83528E using a spectrum analyzer and a signal generator in conjunction with the appropriate power amplifiers and antennas. The transmitting antenna was located inside of a shielded control chamber located adjacent to the Receiving chamber. Reference levels were measured through the 26 inch by 26 inch opening in the shielded enclosure without the test sample in place. The minimum reference level recorded was 100dB at 20MHz, 105dB at 30MHz, 4-10GHz and 110dB at 40MHz-2GHz. References were made with the antennas positioned in horizontal polarity separated by 2 meters 20-800MHz and 1 meter 1-10GHz.

The test sample was compressed 10% when under test.

The test levels were then recorded at each frequency and attenuation values were determined by calculating the difference between the reference level and the test level.

Dynamic Range is determined by placing a solid plate between the two chambers, measuring the amplitude of each frequency, then subtracting that from the reference level.



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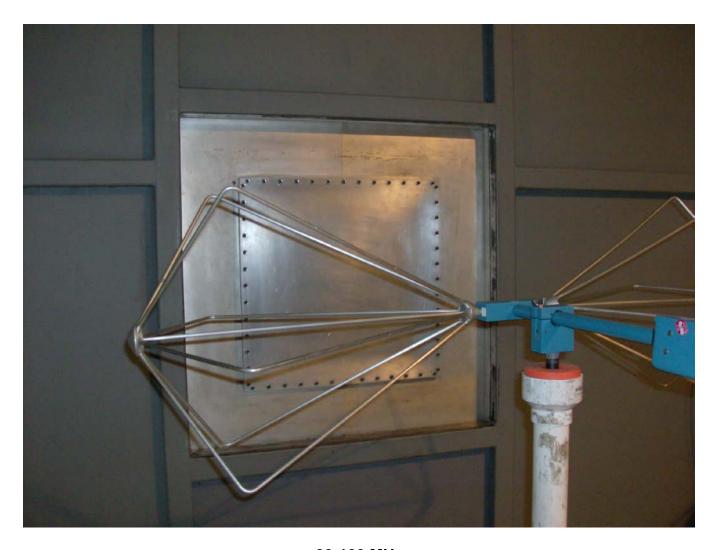
APPENDIX C - Supplemental Data

Frequency (MHz)	Reference Level	Dynamic Range	SSP550-45 (SE)
20	100	133.5	125.1
30	105	138.9	133.9
40	110	143.8	137.2
60	110	143.4	137.3
80	110	142.8	137.8
100	110	143.4	136.7
200	110	142.3	137.3
400	110	142.5	136.2
601	110	142.7	130.8
800	110	142.2	134.7
1000	110	132	131.2
2000	110	131.4	130.4
4100	105	126.1	125.2
6000	105	126.3	125
8000	105	126	125.3
10000	105	126.5	125.5

Test Results



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20-100 MHz



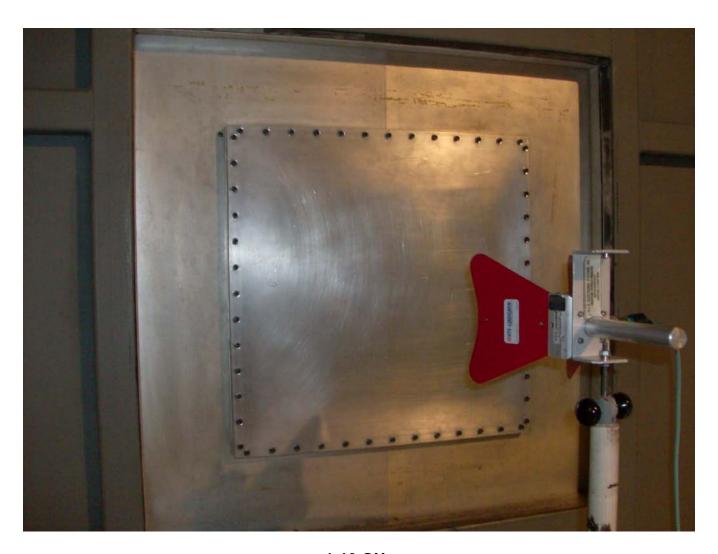
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200-800 MHz



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1-10 GHz